

Search Notes

Application/Control No.

10/762,230

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

YAW, LARRY

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	215		
15	229.11		
15	229.12		
15	229.13	8/22/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, OCR, JPO, EPO, DERWENT		
Inventor name search	8/22/2005	RC